

Search Notes

Application/Control No.

10/029,769

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under
Reexamination

RILEY ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR